

DETAILED ACTION

EXAMINER'S AMENDMENT

1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it **MUST** be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with Enoch E. Peavey on November 24, 2008.

The application has been amended as follows:

In the Specification:

In paragraph 009, line 24, the words "(see claim 1)" have been deleted

In paragraph 0013, line 4, the words "(see claim 2)" have been deleted

In paragraph 0014, line 4, the words "(see claim 3)" have been deleted

In paragraph 0015, line 3, the words "(see claim 4)" have been deleted

In paragraph 0016, lines 5-6, the words "(see claim 5)" have been deleted

In paragraph 0017, line 6, the words "(see claim 6)" have been deleted

In paragraph 0018, line 6, the words "(see claim 7)" have been deleted

In paragraph 0019, lines 5-6, the words "(see claim 8)" have been deleted

In paragraph 0020, line 5, the words "(see claim 9)" have been deleted

In paragraph 0020, line 10, the words "(see claim 10)" have been deleted

In paragraph 0020, line 15, the words "(see claim 11)" have been deleted

In paragraph 0021, line 16, the words "(see claim 12)" have been deleted

In paragraph 0026, line 10, the words "(see claim 13)" have been deleted

In paragraph 0027, lines 4-5, the words "(see claim 14)" have been deleted

In paragraph 0027, lines 13-14, the words "(see claim 15)" have been deleted

In paragraph 0027, lines 16-17, the words "(see claim 16)" have been deleted

In paragraph 0028, line 20, the words "(see claim 17)" have been deleted

Allowable Subject Matter

2. **Claims 1-6, 10-11 and 15-16** are allowed.
3. The following is an examiner's statement of reasons for allowance:

In terms of claim 1, the prior art of record does not teach alone or in combination a image sensor test system comprising a contact arm configured to pick up and move the inverted image sensor inverted by the first inverter, the contact arm being configured to bring input/output terminals of the inverted image sensor into electrical contact with a contact of the test head; an attachment portion configured to attach the light source and the test head to the image sensor test system so as to place the light source and the test head beneath the image sensor, in combination with all other elements in claim 1.

As to claims 2-5, the claims are allowed as they further limit allowed claim 1.

In terms of claim 6, the prior art of record does not teach alone or in combination a image sensor test system wherein each of the first and second inverters comprises a rotation mechanism, wherein the rotation mechanism comprises a pinion

gear which supports the first holder and a rack which intermeshes with the pinion gear and converts linear force supplied to the rack gear to rotational force so as to rotate the first holder, in combination with all other elements in claim 6.

In terms of claim 10, the prior art of record does not teach alone or in combination an image sensor test system comprising a judging means device configured to judge an emission pattern of light emitted from the light source and an input pattern of electrical signals input from a contact of the test head based on image information obtained by the imaging device, in combination with all other elements in claim 10.

As to claim 11, the claims are allowed as they further limit allowed claim 10.

In terms of claim 15, the prior art of record does not teach alone or in combination a method for an image sensor comprising a judgment step of judging an emission pattern of light emitted from the light source and an input pattern of electrical signals input from a contact of the test head based on the device type information obtained in obtaining the image of the image sensor, in testing the inverted image sensor, emitting light to the light receiving surface of the image sensor in accordance with the emission pattern and inputting and outputting electrical signals between the contact of the test head and the image sensor in accordance with the input pattern, in combination with all other elements in claim 15.

As to claim 16, the claims are allowed as they further limit allowed claim 15.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

4. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

Document Number Number-Kind Code e.g. 0500004 A1	Date MM-YYYY	Name	Classification
6,359,454	03-2002	Khoury, Theodore A.	324/754
5,644,245	07-1997	Saitoh et al.	324/754

5. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Richard Isla-Rodas whose telephone number is (571) 272-5056. The examiner can normally be reached on Monday through Friday 8 am to 4:30 pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Ha Nguyen can be reached on (571) 272-1678. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only.

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Richard Isla-Rodas
November 24, 2008
/Ha T. Nguyen/

Supervisory Patent Examiner, Art Unit 2829